## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
1051161711893601	SCHULTZ, JUERGENAVENDANO ET AL.
Examiner	Art Unit
DEVONA E FAULKDEVONA E FAULK	26152614

SEARCHED			
Class	Subclass	Date	Examiner
381	98,103,94.1-94.3	8/29/10	DEF
704381	224-22686,91,92	8/29/102/3/06	DEFDEF
381	86,91,92	4/9/2008	DEF
381	86,91,92,111,122	6/7,7/091	DEF
381	86,91,92,111,122	12/4/09	DEF

SEARCH NOTES			
Search Notes	Date	Examiner	
assignee/inventor search	8/29/10	DEF	
used same workspace that was used for parent caseAssignee/Inventor	8/29/102/3/07	DEFDEF	
search			
Reviewed art submitted on IDS	2/3/07	DEF	
Additional search	10/18/07	DEF	
Reviewed applicant's arguments/maintained rejection	4/9/2008	DEF	
additional search	6/7,17/09	DEF	
reviewed applicant's arguments/ maintained rejection	12/4/09	DEF	
additional search	6/7/10	DEF	
additonal search	9/7/10	DEF	

	INTERFERENCE SEA	RCH	
Class	Subclass	Date	Examiner

/DEVONA E FAULK/ Primary Examiner.Art Unit 2614/DEVONA E FAULK/ Primary Examiner.Art Unit 2614

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